

Abstract of the Disclosure:

A method and a device for testing an integrated circuit are defined by the fact that the testing of the integrated circuit is begun by a self-test device contained in the integrated  
5 circuit before the integrated circuit is connected to an external testing device that reads out and/or evaluates the results of the self test. The integrated circuit and the wafer are constructed in such a way that this is readily possible with little outlay. An integrated circuit that includes the  
10 self-test device and a wafer including such integrated circuits is also disclosed.

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